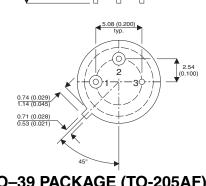


0.41 (0.016)



# **N-CHANNEL ENHANCEMENT MODE TRANSISTOR**

#### **FEATURES**

- V<sub>(BR)DSS</sub> = 200V
- I<sub>D</sub> = 5.5A
- R<sub>DSON</sub> = 0.40Ω

#### TO-39 PACKAGE (TO-205AF)

**Underside View** 

PIN 1 – Source PIN 2 – Gate PIN 3 – Drain

### ABSOLUTE MAXIMUM RATINGS (T<sub>case</sub> = 25°C unless otherwise stated)

V <sub>DS</sub>	Drain-Source Voltage	200V		
V <sub>GS</sub>	Gate-Source Voltage	±20V		
I <sub>D</sub>	Drain Current Continuous T <sub>Case</sub> = 25°C	5.5A		
	T <sub>Case</sub> = 100°C	3.5A		
I <sub>DM</sub>	Drain Current Pulsed	22A		
P <sub>D</sub>	Total Device Dissipation @ T <sub>Case</sub> = 25°C	25W		
	T <sub>Case</sub> = 100°C	10W		
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range	–55 to +150°C		
THERMAL C	HARACTERISTICS			
$R_{ extsf{ heta}JC}$	Thermal Resistance Junction to Case	5.0°C/W		
$R_{ extsf{ heta}JA}$	Thermal Resistance Junction to Ambient	175°C/W		
ΤL	Maximum Lead Temperature 1.6mm from Case for	300°C		
	10 secs.			

Semelab Plc reserves the right to change test conditions, parameter limits and package dimensions without notice. Information furnished by Semelab is believed to be both accurate and reliable at the time of going to press. However Semelab assumes no responsibility for any errors or omissions discovered in its use. Semelab encourages customers to verify that datasheets are current before placing orders.

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## **IRFF230** 2N6798





#### **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise stated)

	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain–Source Breakdown Voltage	$V_{GS} = 0$	I <sub>D</sub> = 1mA	200			v
V <sub>GS(th)</sub>	Gate Thresshold Voltage	V <sub>DS</sub> =V <sub>GS</sub>	$I_D = 250 \mu A$	2.0		4.0	v
I <sub>GSS</sub>	Gate-Body Leakage	$V_{DS} = 0$	$V_{GS} = \pm 20V$			±100	nA
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =0.8 x V <sub>(BR)DSS</sub>				25	
			T <sub>j</sub> = 125°C			250	μΑ
r <sub>DS(on)</sub>	Drain–Source On–Resistance <sup>1</sup>	V <sub>GS</sub> = 10V	I <sub>D</sub> = 3.5A		0.25	0.4	Ω
gf <sub>s</sub>	Forward Transconductance <sup>1</sup>	V <sub>DS</sub> = 15V	I <sub>D</sub> = 3.5A	2.5	3.0		s(ឋ)
C <sub>iss</sub>	Input Capacitance		V – 0		600		
C <sub>oss</sub>	Output capacitance	$V_{DS} = 25V$ $V_{GS} = 0$ f = 1.0MH <sub>7</sub>			250		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				80		1
t <sub>don</sub>	Turn–On Delay Time	V <sub>DD</sub> = 77V	$RL = 22\Omega$		8	30	
t <sub>r</sub>	RiseTime	I <sub>D</sub> = 3.5A	$V_{GEN} = 10V$		42	50	
t <sub>d(of)</sub>	Turn off Delay Time	R <sub>G</sub> = 7.5 ohms			12	50	ns
t <sub>f</sub>	FallTime				30	40	
	SOURCE DRAIN DIODE RATING	CHARACTE	RISTICS				
V <sub>SD</sub>	Diode Forward Voltage <sup>1</sup>	I <sub>F</sub> = 5.5A	$V_{GS} = 0$			1.4	V
I <sub>S</sub>	Continues Current					5.5	_
I <sub>SM</sub>	Pulsed Current <sup>2</sup>	1				22	A
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 5.5A	$V_{DD} = 50V$		150	500	ns
Q <sub>rr</sub>	Reverse Recovered Charge	dl <sub>F</sub> /DT = 100	)A/μS			6	μC

1) Pulse test : Pulse Width <  $300\mu$ s ,Duty Cycle < 2%

2) Pulse width limited by maximum juction temperature

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